

**Search Notes**

Application/Control No.

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Examiner

Pierre-Michel Bataille

Applicant(s)/Patent under  
Reexamination

LEE, WOO-HYONG

Art Unit

2186

**SEARCHED**

Class	Subclass	Date	Examiner
711	170 ; 169	2/2/2007	PMB
707	205 ; 206		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST Search	2/2/2007	PMB